

Notice of References Cited	Application/Control No. 10/743,409	Applicant(s)/Patent Under Reexamination HATADA ET AL.	
	Examiner Kaj K. Olsen	Art Unit 1753	Page 1 of 1

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*	B	US-4,030,190	06-1977	Varker, Kenneth James	29/852
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*	D	US-5,331,310	07-1994	Stetter et al.	340/632
*	E	US-4,112,893	09-1978	Anzai, Makoto	123/689
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*	G	US-6,673,223	01-2004	Kunimoto et al.	204/426
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NON-PATENT DOCUMENTS

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	U	Skoog et al, Principles of Instrumental Analysis, 5th Edition, 1998, pp. 53-55.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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